

**Search Notes**

Application/Control No.

09/938,982

Examiner

Jacques Veillard

Applicant(s)/Patent under  
Reexamination

MURTHY ET AL.

Art Unit

2165

**SEARCHED**

Class	Subclass	Date	Examiner
Updated	Search	6/26/2005	J.V
707	2, 3, 7	6/26/2005	J.V
707	10, 102	6/26/2005	J.V
707	104.1, 20	6/26/2005	J.V
707	204	6/26/2005	J.V
709	223,224	6/26/2005	J.V
709	228	6/26/2005	J.V
715	513, 530	6/26/2005	J.V

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated East Database Search.	6/26/2005	J.V
Search: US. Pat., US. Pub., EPO, JPO, Derwent, IBM TDB, and NPL.	6/26/2005	J.V
ACM and IEEE Database Electronic Search.	6/26/2005	J.V

**INTERFERENCE SEARCHED**

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